

# L6385

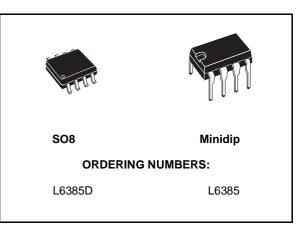
## HIGH-VOLTAGE HIGH AND LOW SIDE DRIVER

- HIGH VOLTAGE RAIL UP TO 600 V
- dV/dt IMMUNITY +- 50 V/nsec IN FULL TEM-PERATURE RANGE
- DRIVER CURRENT CAPABILITY: 400 mA SOURCE, 650 mA SINK
- SWITCHING TIMES 50/30 nsec RISE/FALL WITH 1nF LOAD
- CMOS/TTL SCHMITT TRIGGER INPUTS WITH HYSTERESIS AND PULL DOWN
- UNDER VOLTAGE LOCK OUT ON LOWER AND UPPER DRIVING SECTION
- INTERNAL BOOTSTRAP DIODE
- OUTPUTS IN PHASE WITH INPUTS

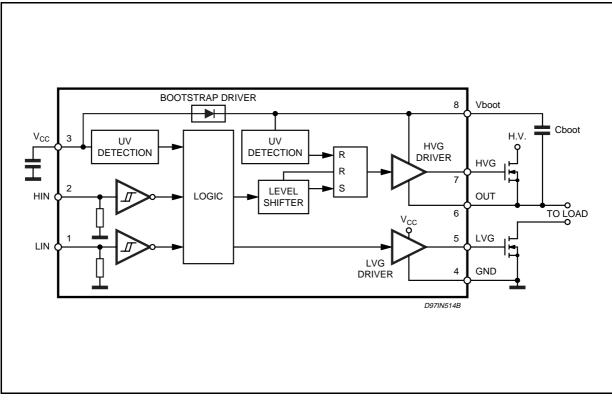
### DESCRIPTION

The L6385 is an high-voltage device, manufactured with the BCD"OFF-LINE" technology. It has a Driver structure that enables to drive inde-

### **BLOCK DIAGRAM**



pendent referenced N Channel Power MOS or IGBT. The Upper (Floating) Section is enabled to work with voltage Rail up to 600V. The Logic Inputs are CMOS/TTL compatible for ease of interfacing with controlling devices.



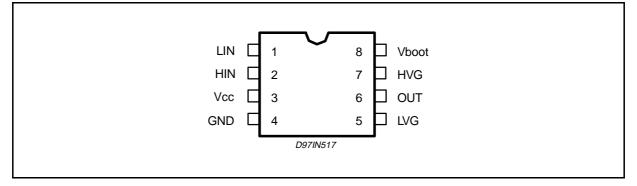
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### **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
Vout	Output Voltage	-3 to Vboot - 18	V
Vcc	Supply Voltage	- 0.3 to +18	V
Vboot	Floating Supply Voltage	- 1 to 618	V
Vhvg	Upper Gate Output Voltage	- 1 to Vboot	V
Vlvg	Lower Gate Output Voltage	-0.3 to Vcc +0.3	V
Vi	Logic Input Voltage	-0.3 to Vcc +0.3	V
dVout/dt	Allowed Output Slew Rate	50	V/ns
Ptot	Total Power Dissipation (Tj = 85 °C)	750	mW
Tj	Junction Temperature	150	°C
Ts	Storage Temperature	-50 to 150	°C

Note: ESD immunity for pins 6, 7 and 8 is guaranteed up to 900V (Human Body Model)

### **PIN CONNECTION**



### THERMAL DATA

Symbol	Parameter	SO8	Minidip	Unit
R <sub>th j-amb</sub>	Thermal Resistance Junction to Ambient	150	100	°C/W

### **PIN DESCRIPTION**

N.	Name	Туре	Function			
1	LIN	I	Lower Driver Logic Input			
2	HIN	I	Jpper Driver Logic Input			
3	Vcc	I	Low Voltage Power Supply			
4	GND		Ground			
5	LVG (*)	0	Low Side Driver Output			
6	VOUT	0	Upper Driver Floating Reference			
7	HVG (*)	0	High Side Driver Output			
8	Vboot		Bootstrap Supply Voltage			

(\*) The circuit guarantees 0.3V maximum on the pin (@ Isink = 10mA). This allows to omit the "bleeder" resistor connected between the gate and the source of the external MOSFET normally used to hold the pin low.



### **RECOMMENDED OPERATING CONDITIONS**

Symbol	Pin	Parameter	Test Condition	Min.	Тур.	Max.	Unit
Vout	6	Output Voltage		Note 1		580	V
Vboot- Vout	8	Floating Supply Voltage		Note 1		17	V
fsw		Switching Frequency	HVG,LVG load CL = 1nF			400	kHz
Vcc	2	Supply Voltage				17	V
Tj		Junction Temperature		-45		125	°C

Note 1: If the condition Vboot - Vout < 18V is guaranteed, Vout can range from -3 to 580V.

### ELECTRICAL CHARACTERISTICS AC Operation (Vcc = 15V; Tj = 25°C)

Symbol	Pin	Parameter	Test Condition	Min.	Тур.	Max.	Unit
ton	1 vs 5	High/Low Side Driver Turn-On Propagation Delay	Vout = 0V		110		ns
toff	2 vs 7	High/Low Side Driver Turn-Off Propagation Delay	Vout = 600V		105		ns
tr	7,5	Rise Time	CL = 1000pF		50		ns
tf	7,5	Fall Time	CL = 1000pF		30		ns

### DC OPERATION (Vcc = 15V; Tj = 25°C)

Symbol	Pin	Parameter Test Condition		Min.	Тур.	Max.	Unit
Low Sup	oply Vo	oltage Section					
Vcc	3	Supply Voltage				17	V
Vccth1		Vcc UV Turn On Threshold		9.1	9.6	10.1	V
Vccth2		Vcc UV Turn Off Threshold		7.9	8.3	8.8	V
Vcchys		Vcc UV Hysteresis			1.3		V
lqccu		Undervoltage Quiescent Supply Current	$Vcc \le 9V$		150	220	μΑ
lqcc		Quiescent Current	Vcc = 15V		250	320	μA
R <sub>dson</sub>		Bootstrap Driver on Resistance (*)	Vcc ≥ 12.5V		125		Ω
Bootstra	apped	supply Voltage Section					
VBS	8	Bootstrap Supply Voltage				17	V
VBSth1		VBS UV Turn On Threshold		8.5	9.5	10.5	V
VBSth2		VBS UV Turn Off Threshold		7.2	8.2	9.2	V
VBShys		VBS UV Hysteresis			1.3		V
IQBS		VBS Quiescent Current	HVG ON			200	μA
ILK		High Voltage Leakage Current	VS = VB = 600V			10	μΑ
High/Lov	w Side	Driver					
lso	5,7	Source Short Circuit Current	$VIN = Vih (tp < 10\mu s)$	300	400		mA
lsi		Sink Short Circuit Current	$VIN = Vil (tp < 10\mu s)$	450	650		mA
Logic In	puts						
Vil	2,3	Low Level Logic Threshold Voltage				1.5	V
Vih		High Level Logic Threshold Voltage		3.6			V
lih		High Level Logic Input Current	VIN = 15V		50	70	μA
lil		Low Level Logic Input Current	VIN = 0V			1	μA

(\*) R<sub>DSON</sub> is tested in the following way:  $R_{DSON} = \frac{(V_{CC} - V_{CBOOT1}) - (V_{CC} - V_{CBOOT2})}{I_1(V_{CC}, V_{CBOOT1}) - I_2(V_{CC}, V_{CBOOT2})}$ 

where  $I_1$  is pin 8 current when  $V_{CBOOT} = V_{CBOOT1}$ ,  $I_2$  when  $V_{CBOOT} = V_{CBOOT2}$ .

Figure 1. Input/Output Timing Diagram

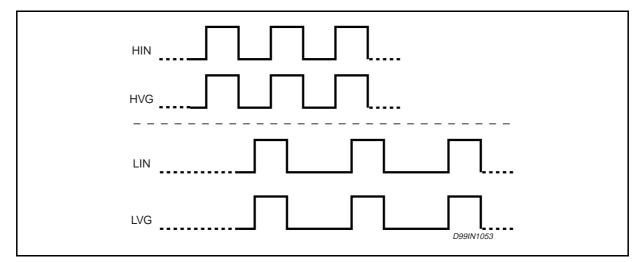
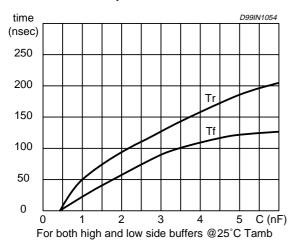


Figure 2. Typical Rise and Fall Times vs. Load Capacitance



### **BOOTSTRAP DRIVER**

A bootstrap circuitry is needed to supply the high voltage section. This function is normally accomplished by a high voltage fast recovery diode (fig. 4a). In the L6385 a patented integrated structure replaces the external diode. It is realized by a high voltage DMOS, driven synchronously with the low side driver (LVG), with in series a diode, as shown in fig. 4b

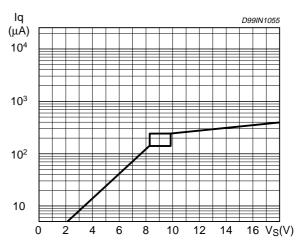
An internal charge pump (fig. 4b) provides the DMOS driving voltage .

The diode connected in series to the DMOS has been added to avoid undesirable turn on of it.

### **CBOOT** selection and charging:

To choose the proper  $C_{\text{BOOT}}$  value the external MOS can be seen as an equivalent capacitor.

Figure 3. Quiescent Current vs. Supply Voltage



This capacitor  $C_{\text{EXT}}$  is related to the MOS total gate charge :

$$C_{EXT} = \frac{Q_{gate}}{V_{gate}}$$

The ratio between the capacitors  $C_{EXT}$  and  $C_{BOOT}$  is proportional to the cyclical voltage loss . It has to be:

### C<sub>BOOT</sub>>>>C<sub>EXT</sub>

e.g.: if  $Q_{gate}$  is 30nC and  $V_{gate}$  is 10V,  $C_{EXT}$  is 3nF. With  $C_{BOOT}$  = 100nF the drop would be 300mV.

If HVG has to be supplied for a long time, the  $C_{\text{BOOT}}$  selection has to take into account also the

leakage losses.

e.g.: HVG steady state consumption is lower than 200 $\mu$ A, so if HVG T<sub>ON</sub> is 5ms, C<sub>BOOT</sub> has to supply 1 $\mu$ C to C<sub>EXT</sub>. This charge on a 1 $\mu$ F capacitor means a voltage drop of 1V.

The internal bootstrap driver gives great advantages: the external fast recovery diode can be avoided (it usually has great leakage current). This structure can work only if V<sub>OUT</sub> is close to GND (or lower) and in the meanwhile the LVG is on. The charging time ( $T_{charge}$ ) of the C<sub>BOOT</sub> is the time in which both conditions are fulfilled and it has to be long enough to charge the capacitor.

The bootstrap driver introduces a voltage drop due to the DMOS  $R_{DSON}$  (typical value: 125 Ohm). At low frequency this drop can be neglected. Anyway increasing the frequency it must be taken in to account.

The following equation is useful to compute the **Figure 4. Bootstrap Driver.** 

drop on the bootstrap DMOS:

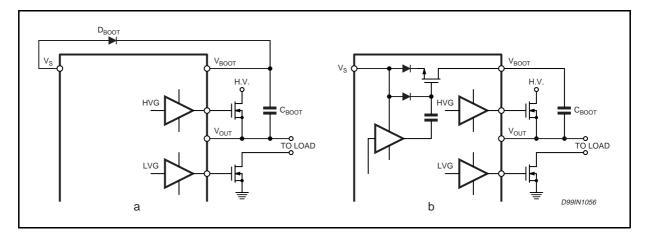
$$V_{drop} = I_{charge} R_{dson} \rightarrow V_{drop} = \frac{Q_{gate}}{T_{charge}} R_{dson}$$

where  $Q_{gate}$  is the gate charge of the external power MOS,  $R_{dson}$  is the on resistance of the bootstrap DMOS, and  $T_{charge}$  is the charging time of the bootstrap capacitor.

For example: using a power MOS with a total gate charge of 30nC the drop on the bootstrap DMOS is about 1V, if the  $T_{charge}$  is 5µs. In fact:

$$V_{drop} = \frac{30nC}{5\mu s} \cdot 125\Omega \sim 0.8V$$

 $V_{drop}$  has to be taken into account when the voltage drop on  $C_{BOOT}$  is calculated: if this drop is too high, or the circuit topology doesn't allow a sufficient charging time, an external diode can be used.





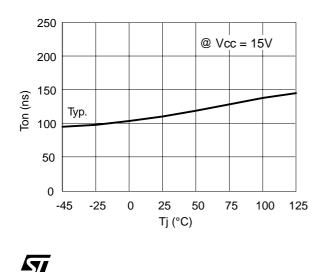
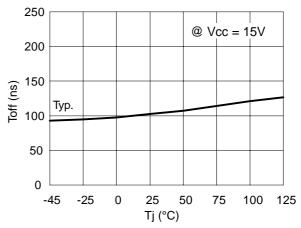


Figure 6. Turn Off Time vs. Temperature



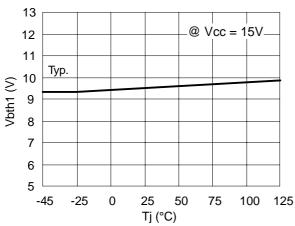
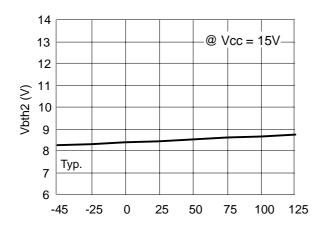
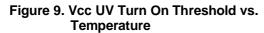
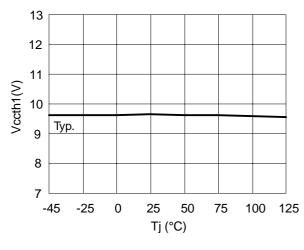


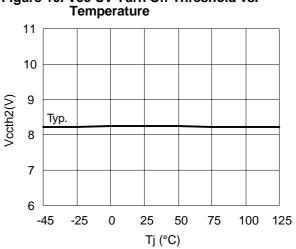
Figure 7. VBOOT UV Turn On Threshold vs. Temperature



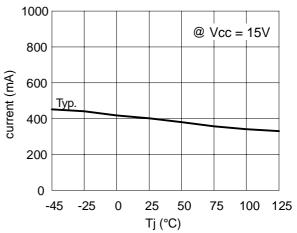














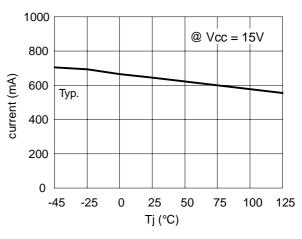
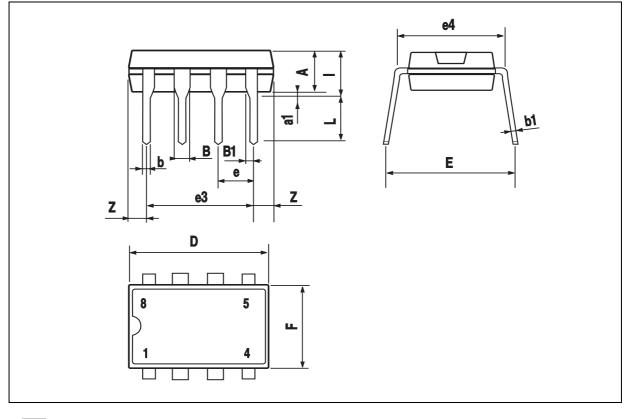


Figure 10. Vcc UV Turn Off Threshold vs. Temperature

DIM.	mm			inch			
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А		3.32			0.131		
a1	0.51			0.020			
В	1.15		1.65	0.045		0.065	
b	0.356		0.55	0.014		0.022	
b1	0.204		0.304	0.008		0.012	
D			10.92			0.430	
Е	7.95		9.75	0.313		0.384	
е		2.54			0.100		
e3		7.62			0.300		
e4		7.62			0.300		
F			6.6			0.260	
I			5.08			0.200	
L	3.18		3.81	0.125		0.150	
Z			1.52			0.060	

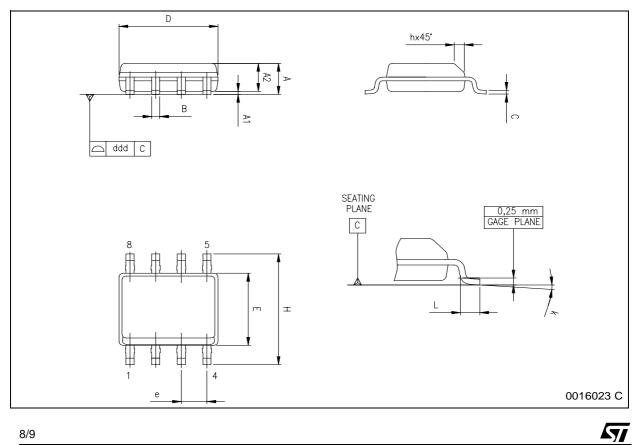
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### L6385

DIM.		mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
Α	1.35		1.75	0.053		0.069	
A1	0.10		0.25	0.004		0.010	
A2	1.10		1.65	0.043		0.065	
В	0.33		0.51	0.013		0.020	
С	0.19		0.25	0.007		0.010	
D <sup>(1)</sup>	4.80		5.00	0.189		0.197	
E	3.80		4.00	0.15		0.157	
е		1.27			0.050		
н	5.80		6.20	0.228		0.244	
h	0.25		0.50	0.010		0.020	
L	0.40		1.27	0.016		0.050	
k		0	° (min.),	8° (max	.)		
ddd			0.10			0.004	
Note: (1) Dimensions D does not include mold flash, protru- sions or gate burrs. Mold flash, potrusions or gate burrs shall not exceed 0.15mm (.006inch) in total (both side).							

# **OUTLINE AND MECHANICAL DATA SO-8**



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